

# **Japan TC Chapter Flexible Hybrid Electronics (FHE) Global Technical Committee**

**Liaison Report | October 1, 2021**

**V.1.0**

# Meeting Information



- Last meeting
  - Monday, September 13, 2021 at the SEMI Standards Japan Autumn Meetings
    - Web Conference
- Next meeting
  - Friday, January 14, 2022 at the SEMI Standards Japan Winter Meetings
    - Web Conference/SEMI Japan office, Tokyo (TBD)

**<http://www.semi.org/en/standards-events>**

# Leadership Changes

- None

# Committee Structure Changes

- New TF: FHE Terminology TF

## **CHARTER:**

Explore, evaluate, discuss, and create consensus based FHE standards covering design rules, manufacturing flow, test verification methods, specifications, guidelines, and practices that, through voluntary compliance, will:

- promote mutual understanding and improve communication between users and suppliers of FHE integrated systems, components, materials, and testing capabilities
- enhance the design correctness and capability so as to improve the manufacturing efficiency and capability

## **SCOPE:**

- To explore and develop standards that pertain to common criteria, guidelines, methods for design and test verification of FHE systems, components, materials, production equipment, and performance specification. It will seek to support the supply chain and ecosystem needs for improving FHE product / process yield and quality.
- To include liaisons and synergies with the other SEMI technical committees for the development of FHE technology related standards.
- In addition, the committee will also facilitate any industry initiatives towards product standardization needs.

# Organization Chart

## Flexible Hybrid Electronics (FHE) Japan TC Chapter

C: Satoshi Maeda – TOYOBO CO., LTD

C: Ryoichi Watanabe – Japan Display Inc.

C: Tadahiro Furukawa – Yamagata University

## FHE Terminology TF

**(NEW)**

C: Ryoichi Watanabe – Japan Display Inc.

C: Satoshi Maeda – TOYOBO CO., LTD

C: Tadahiro Furukawa – Yamagata University

# Committee Highlights

- New Business: Mr. Maeda introduces the concept of texture measurement standardization
- TF: FHE Terminology TF has been approved.
- SNARF: By the above approvement, next step will be to create a new SNARF.
  - Suggestion will be made by co-chairs until the next committee.

# Ballot Results



Doc #	Document Title	TC Chapter Action
None		

Note 1: **Passed** ballots and line items will be submitted to the ISC Audit & Review Subcommittee for procedural review.

Note 2: **Failed** ballots and line items were returned to the originating task forces for re-work and re-balloting or abandoning.

# Activities Approved via GCS between Meetings

Doc #	Type	SC/TF/CFG	Title/Details
None			



# Authorized Activities



Doc #	Type	SC/TF/CFG	Document Title/Details
None			

**#1: SNARFs and TFOFs are available for review on the SEMI Web site at:**

**<http://downloads.semi.org/web/wstdsbal.nsf/TFOFSNARF>**

# Other Activities Outside the Letter Ballot Process

- None

# Authorized Ballots

Doc #	When	TF	Document Title/Details
None			

# Task Force Highlights



# Open SNARF(s)

- None

# SNARF(s) Abolished

Doc #	SC/TF/CFG	Title/Details
None		

# 5-Year Review

Designation #	Standard Title	Action By	Assigned to
None			

# Thank you!

Staff Contact: Keigo Nakajima  
[knakajima@semi.org](mailto:knakajima@semi.org)

---

